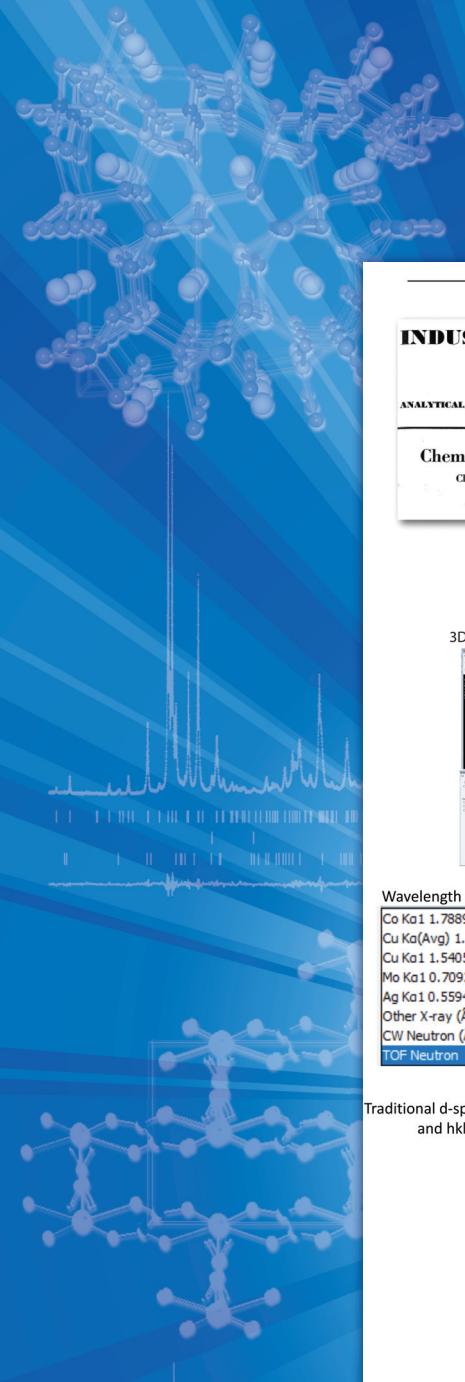


# Powder Diffraction PDJ

*Journal of Materials Characterization*



**1938**

**INDUSTRIAL and ENGINEERING CHEMISTRY**  
ANALYTICAL EDITION • Harrison E. Howe, Editor

**Chemical Analysis by X-Ray Diffraction**  
Classification and Use of X-Ray Diffraction Patterns  
J. D. HANAWALT, H. W. RINN, and L. K. FREVEL  
The Dow Chemical Company, Midland, Mich.

**1941**

$d$ in Å	$\frac{1}{d}$	$d$ in Å	$\frac{1}{d}$
4.00	0.99	2.47	0.40
3.40	1.16	2.82	0.35
3.20	1.20	3.20	0.32
3.10	1.25	3.37	0.30
2.95	1.36	3.52	0.28
2.85	1.43	3.63	0.26
2.75	1.51	3.75	0.24
2.65	1.59	3.86	0.22
2.55	1.66	4.00	0.20
2.45	1.73	4.12	0.18
2.35	1.80	4.24	0.16
2.25	1.87	4.36	0.14
2.15	1.94	4.47	0.12
2.05	2.00	4.58	0.10
1.95	2.06	4.69	0.08
1.85	2.12	4.80	0.06
1.75	2.18	4.91	0.04
1.65	2.24	5.02	0.02
1.55	2.30	5.13	-
1.45	2.36	5.24	-
1.35	2.42	5.35	-
1.25	2.48	5.46	-
1.15	2.54	5.57	-
1.05	2.60	5.68	-
0.95	2.66	5.79	-
0.85	2.72	5.90	-
0.75	2.78	6.01	-
0.65	2.84	6.12	-
0.55	2.90	6.23	-
0.45	2.96	6.34	-
0.35	3.02	6.45	-
0.25	3.08	6.56	-
0.15	3.14	6.67	-
0.05	3.20	6.78	-
-0.05	3.26	6.89	-
-0.15	3.32	6.99	-
-0.25	3.38	7.10	-
-0.35	3.44	7.21	-
-0.45	3.50	7.32	-
-0.55	3.56	7.43	-
-0.65	3.62	7.54	-
-0.75	3.68	7.65	-
-0.85	3.74	7.76	-
-0.95	3.80	7.87	-
-1.05	3.86	7.98	-
-1.15	3.92	8.09	-
-1.25	3.98	8.20	-
-1.35	4.04	8.31	-
-1.45	4.10	8.42	-
-1.55	4.16	8.53	-
-1.65	4.22	8.64	-
-1.75	4.28	8.75	-
-1.85	4.34	8.86	-
-1.95	4.40	8.97	-
-2.05	4.46	9.08	-
-2.15	4.52	9.19	-
-2.25	4.58	9.30	-
-2.35	4.64	9.41	-
-2.45	4.70	9.52	-
-2.55	4.76	9.63	-
-2.65	4.82	9.74	-
-2.75	4.88	9.85	-
-2.85	4.94	9.96	-
-2.95	5.00	10.07	-
-3.05	5.06	10.18	-
-3.15	5.12	10.29	-
-3.25	5.18	10.40	-
-3.35	5.24	10.51	-
-3.45	5.30	10.62	-
-3.55	5.36	10.73	-
-3.65	5.42	10.84	-
-3.75	5.48	10.95	-
-3.85	5.54	11.06	-
-3.95	5.60	11.17	-
-4.05	5.66	11.28	-
-4.15	5.72	11.39	-
-4.25	5.78	11.50	-
-4.35	5.84	11.61	-
-4.45	5.90	11.72	-
-4.55	5.96	11.83	-
-4.65	6.02	11.94	-
-4.75	6.08	12.05	-
-4.85	6.14	12.16	-
-4.95	6.20	12.27	-
-5.05	6.26	12.38	-
-5.15	6.32	12.49	-
-5.25	6.38	12.60	-
-5.35	6.44	12.71	-
-5.45	6.50	12.82	-
-5.55	6.56	12.93	-
-5.65	6.62	13.04	-
-5.75	6.68	13.15	-
-5.85	6.74	13.26	-
-5.95	6.80	13.37	-
-6.05	6.86	13.48	-
-6.15	6.92	13.59	-
-6.25	6.98	13.70	-
-6.35	7.04	13.81	-
-6.45	7.10	13.92	-
-6.55	7.16	14.03	-
-6.65	7.22	14.14	-
-6.75	7.28	14.25	-
-6.85	7.34	14.36	-
-6.95	7.40	14.47	-
-7.05	7.46	14.58	-
-7.15	7.52	14.69	-
-7.25	7.58	14.80	-
-7.35	7.64	14.91	-
-7.45	7.70	15.02	-
-7.55	7.76	15.13	-
-7.65	7.82	15.24	-
-7.75	7.88	15.35	-
-7.85	7.94	15.46	-
-7.95	8.00	15.57	-
-8.05	8.06	15.68	-
-8.15	8.12	15.79	-
-8.25	8.18	15.90	-
-8.35	8.24	16.01	-
-8.45	8.30	16.12	-
-8.55	8.36	16.23	-
-8.65	8.42	16.34	-
-8.75	8.48	16.45	-
-8.85	8.54	16.56	-
-8.95	8.60	16.67	-
-9.05	8.66	16.78	-
-9.15	8.72	16.89	-
-9.25	8.78	16.90	-
-9.35	8.84	16.91	-
-9.45	8.90	16.92	-
-9.55	8.96	16.93	-
-9.65	9.02	16.94	-
-9.75	9.08	16.95	-
-9.85	9.14	16.96	-
-9.95	9.20	16.97	-
-10.05	9.26	16.98	-
-10.15	9.32	16.99	-
-10.25	9.38	17.00	-
-10.35	9.44	17.01	-
-10.45	9.50	17.02	-
-10.55	9.56	17.03	-
-10.65	9.62	17.04	-
-10.75	9.68	17.05	-
-10.85	9.74	17.06	-
-10.95	9.80	17.07	-
-11.05	9.86	17.08	-
-11.15	9.92	17.09	-
-11.25	9.98	17.10	-
-11.35	10.04	17.11	-
-11.45	10.10	17.12	-
-11.55	10.16	17.13	-
-11.65	10.22	17.14	-
-11.75	10.28	17.15	-
-11.85	10.34	17.16	-
-11.95	10.40	17.17	-
-12.05	10.46	17.18	-
-12.15	10.52	17.19	-
-12.25	10.58	17.20	-
-12.35	10.64	17.21	-
-12.45	10.70	17.22	-
-12.55	10.76	17.23	-
-12.65	10.82	17.24	-
-12.75	10.88	17.25	-
-12.85	10.94	17.26	-
-12.95	11.00	17.27	-
-13.05	11.06	17.28	-
-13.15	11.12	17.29	-
-13.25	11.18	17.30	-
-13.35	11.24	17.31	-
-13.45	11.30	17.32	-
-13.55	11.36	17.33	-
-13.65	11.42	17.34	-
-13.75	11.48	17.35	-
-13.85	11.54	17.36	-
-13.95	11.60	17.37	-
-14.05	11.66	17.38	-
-14.15	11.72	17.39	-
-14.25	11.78	17.40	-
-14.35	11.84	17.41	-
-14.45	11.90	17.42	-
-14.55	11.96	17.43	-
-14.65	12.02	17.44	-
-14.75	12.08	17.45	-
-14.85	12.14	17.46	-
-14.95	12.20	17.47	-
-15.05	12.26	17.48	-
-15.15	12.32	17.49	-
-15.25	12.38	17.50	-
-15.35	12.44	17.51	-
-15.45	12.50	17.52	-
-15.55	12.56	17.53	-
-15.65	12.62	17.54	-
-15.75	12.68	17.55	-
-15.85	12.74	17.56	-
-15.95	12.80	17.57	-
-16.05	12.86	17.58	-
-16.15	12.92	17.59	-
-16.25	12.98	17.60	-
-16.35	13.04	17.61	-
-16.45	13.10	17.62	-
-16.55	13.16	17.63	-
-16.65	13.22	17.64	-
-16.75	13.28	17.65	-
-16.85	13.34	17.66	-
-16.95	13.40	17.67	-
-17.05	13.46	17.68	-
-17.15	13.52	17.69	-
-17.25	13.58	17.70	-
-17.35	13.64	17.71	-
-17.45	13.70	17.72	-
-17.55	13.76	17.73	-
-17.65	13.82	17.74	-
-17.75	13.88	17.75	-
-17.85	13.94	17.76	-
-17.95	14.00	17.77	-
-18.05	14.06	17.78	-
-18.15	14.12	17.79	-
-18.25	14.18	17.80	-
-18.35	14.24	17.81	-
-18.45	14.30	17.82	-
-18.55	14.36	17.83	-
-18.65	14.42	17.84	-
-18.75	14.48	17.85	-
-18.85	14.54	17.86	-
-18.95	14.60	17.87	-
-19.05	14.66	17.88	-
-19.15	14.72	17.89	-
-19.25	14.78	17.90	-
-19.35	14.84	17.91	-
-19.45	14.90	17.92	-
-19.55	14.96	17.93	-
-19.65	15.02	17.94	-
-19.75	15.08	17.95	-
-19.85	15.14	17.96	-
-19.95	15.20	17.97	-
-20.05	15.26	17.98	-
-20.15	15.32	17.99	-
-20.25	15.38	18.00	-
-20.35	15.44	18.01	-
-20.45	15.50	18.02	-
-20.55	15.56	18.03	-
-20.65	15.62	18.04	-
-20.75	15.68	18.05	-
-20.85	15.74	18.06	-
-20.95	15.80	18.07	-
-21.05	15.86	18.08	-
-21.15	15.92	18.09	-
-21.25	15.98	18.10	-
-21.35	16.04	18.11	-
-21.45	16.10	18.12	-
-21.55	16.16	18.13	-
-21.65	16.22	18.14	-
-21.75	16.28	18.15	-
-21.85	16.34	18.16	-
-21.95	16.40	18.17	-
-22.05	16.46	18.18	-
-22.15	16.52	18.19	-
-22.25	16.58	18.20	-
-22.35	16.64	18.21	-
-22.45	16.70	18.22	-
-22.55	16.76	18.23	-
-22.65	16.82	18.24	-
-22.75	16.88	18.25	-
-22.85	16.94	18.26	-
-22.95	17.00	18.27	-
-23.05	17.06	18.28	-
-23.15	17.12	18.29	-
-23.25	17.18	18.30	-
-23.35	17.24	18.31	-
-23.45	17.30	18.32	-
-23.55	17.36	18.33	-
-23.65	17.42	18.34	-
-23.75	17.48	18.35	-
-23.85	17.54	18.36	-
-23.95	17.60	18.37	-
-24.05	17.66	18.38	-
-24.15	17.72	18.39	-
-24.25	17.78	18.40	-
-24.35	17.84	18.41	-
-24.45	17.90	18.42	-
-24.55	17.96	18.43	-
-24.65	18.02	18.44	-
-24.75	18.08	18.45	-
-24.85	18.14	18.46</	

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Capillary Sample Holder

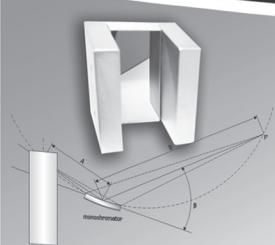


Diamond Anvil Cell Holder



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# Powder Diffraction

An International Journal of Materials Characterization

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On the Cover: Images showing the Powder Diffraction File™ from its beginning in 1941 to today in the Review Article "Chemical analysis by diffraction: the Powder Diffraction File™" (Courtesy of T. G. Fawcett, S. N. Kabekkodu, J. R. Blanton, and T. N. Blanton).

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Featuring  
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